

# **Device Modeling Report**

COMPONENTS: Silicon Carbide Schottky Diode  
PART NUMBER: CSD05120A  
MANUFACTURER: Cree, Inc.  
REMARK: Professional Model

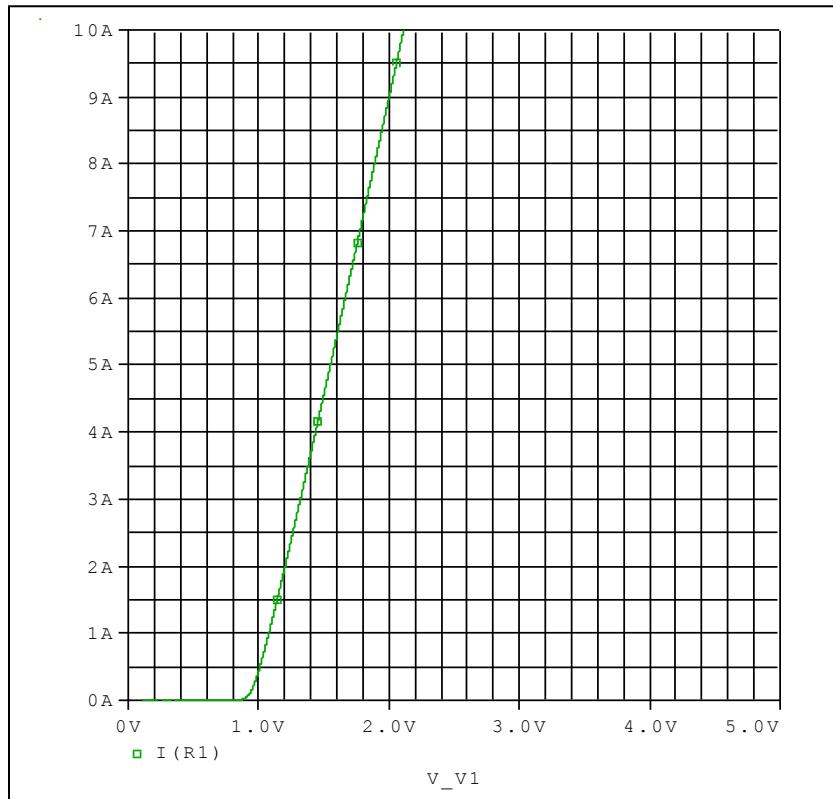


**Bee Technologies Inc.**

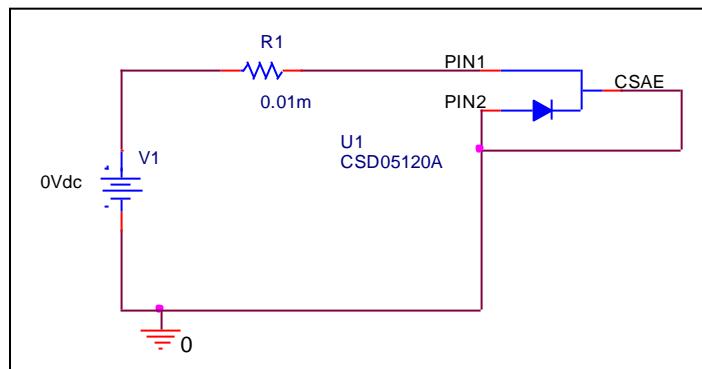
| PSpice model parameter | Model description                           |
|------------------------|---|
| IS                     | Saturation Current                          |
| N                      | Emission Coefficient                        |
| RS                     | Series Resistance                           |
| IKF                    | High-injection Knee Current                 |
| CJO                    | Zero-bias Junction Capacitance              |
| M                      | Junction Grading Coefficient                |
| VJ                     | Junction Potential                          |
| ISR                    | Recombination Current Saturation Value      |
| BV                     | Reverse Breakdown Voltage(a positive value) |
| IBV                    | Reverse Breakdown Current(a positive value) |
| TT                     | Transit Time                                |
| EG                     | Energy-band Gap                             |

## Forward Current Characteristic

### Circuit Simulation Result

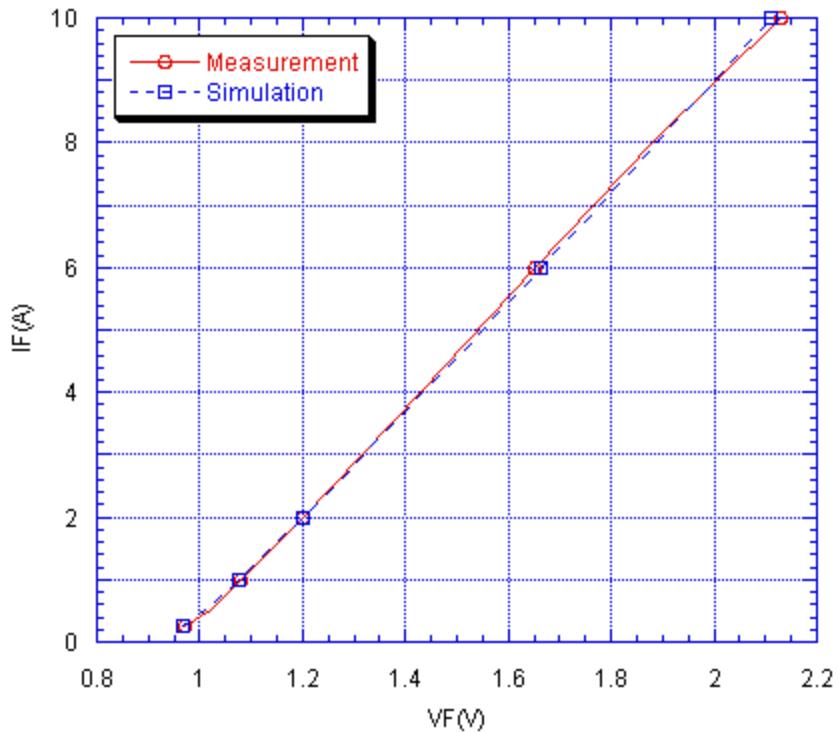


### Evaluation Circuit



## Comparison Graph

Circuit Simulation Result

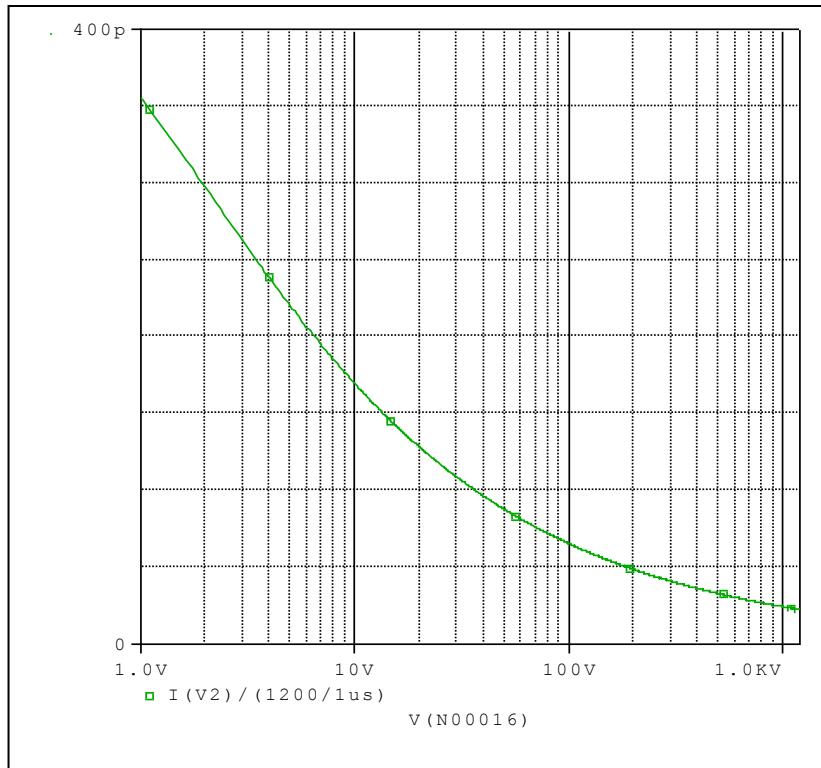


Simulation Result

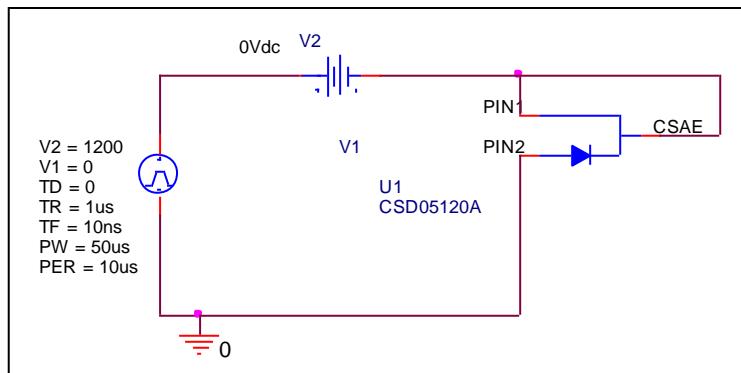
| $I_F(A)$ | $V_F(V)$    |            | Error(%) |
|----------|-------------|------------|----------|
|          | Measurement | Simulation |          |
| 0.25     | 0.970       | 0.967      | -0.310   |
| 0.5      | 1.020       | 1.009      | -1.090   |
| 1        | 1.080       | 1.078      | -0.186   |
| 2        | 1.200       | 1.202      | 0.166    |
| 4        | 1.430       | 1.436      | 0.418    |
| 6        | 1.650       | 1.663      | 0.782    |
| 8        | 1.880       | 1.888      | 0.424    |
| 10       | 2.130       | 2.112      | -0.852   |

## Junction Capacitance Characteristic

### Circuit Simulation Result

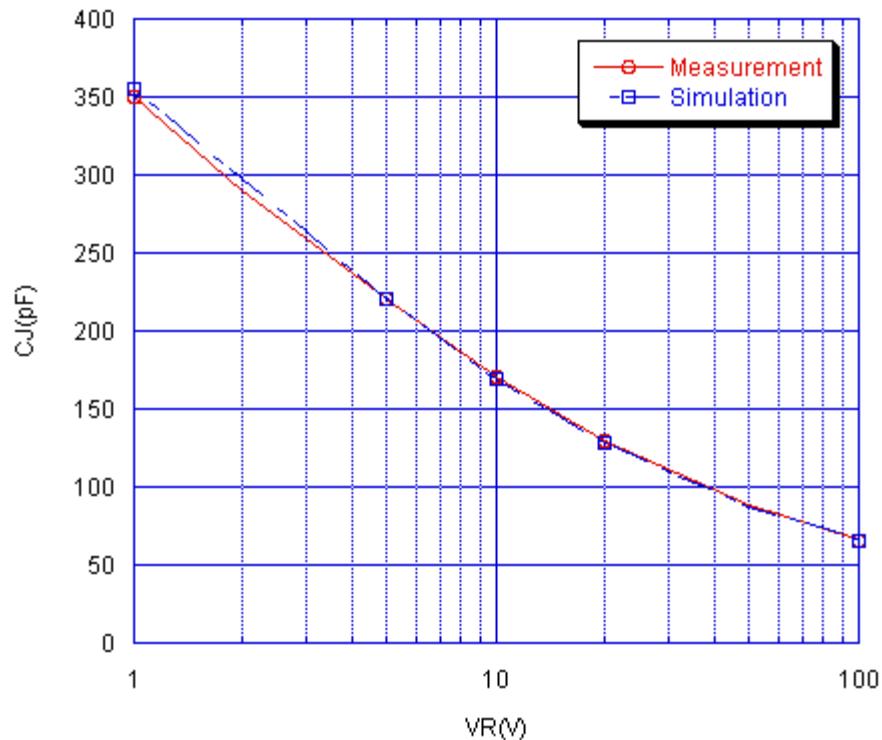


### Evaluation Circuit



## Comparison Graph

### Circuit Simulation Result

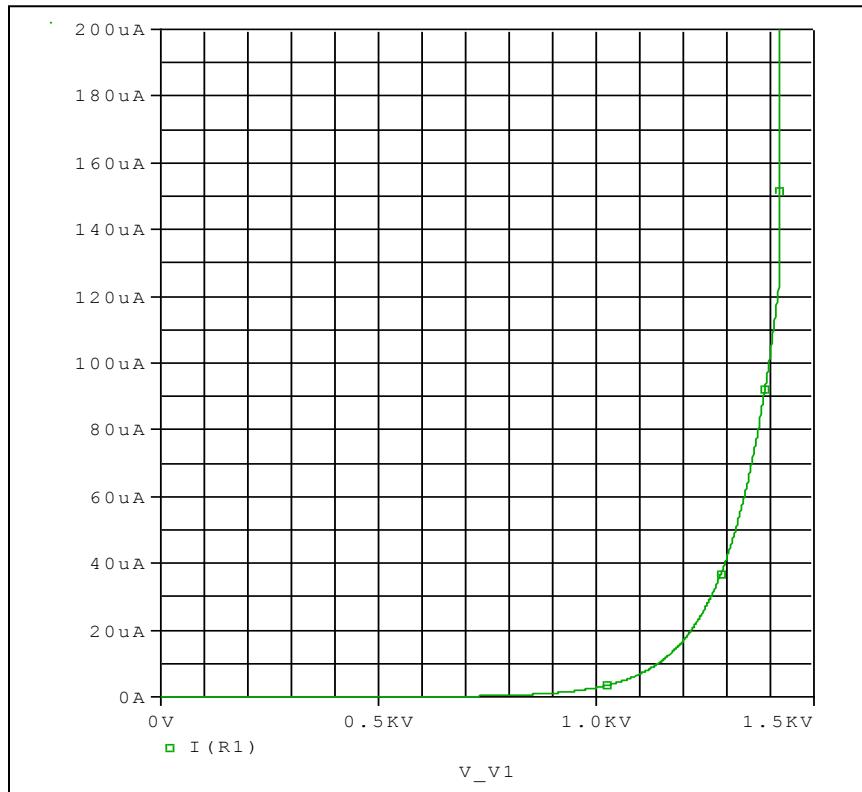


### Simulation Result

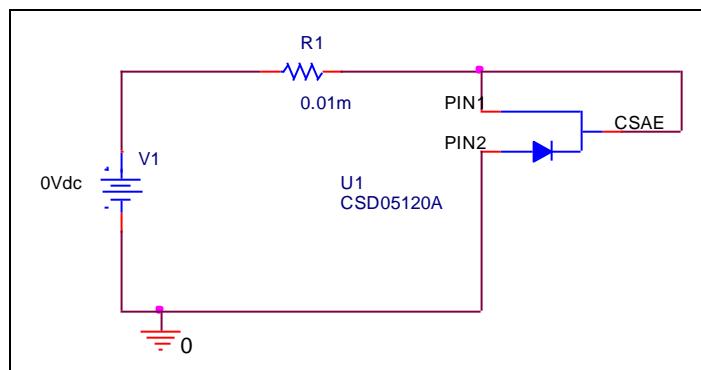
| $V_R$ (V) | Cj (pF)     |            | Error(%) |
|-----------|-------------|------------|----------|
|           | Measurement | Simulation |          |
| 1         | 350.000     | 355.000    | 1.408    |
| 2         | 290.000     | 297.000    | 2.357    |
| 5         | 220.000     | 219.888    | -0.051   |
| 10        | 170.000     | 169.200    | -0.473   |
| 20        | 130.000     | 128.000    | -1.563   |
| 50        | 88.000      | 87.800     | -0.228   |
| 100       | 65.000      | 65.200     | 0.307    |

## Reverse Characteristic

### Circuit Simulation Result

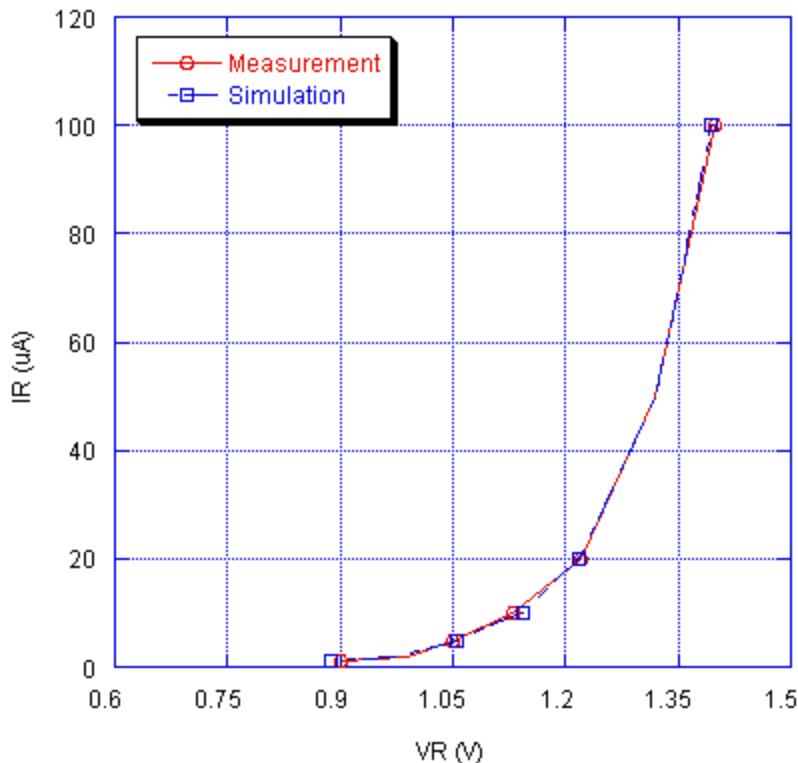


### Evaluation Circuit



## Comparison Graph

Circuit Simulation Result



Simulation Result

| $I_R$ (uA) | $V_R$ (V)   |            | Error(%) |
|------------|-------------|------------|----------|
|            | Measurement | Simulation |          |
| 1          | 0.900       | 0.887      | -1.466   |
| 2          | 0.990       | 0.970      | -2.062   |
| 5          | 1.050       | 1.055      | 0.474    |
| 10         | 1.130       | 1.142      | 1.051    |
| 20         | 1.220       | 1.218      | -0.164   |
| 50         | 1.320       | 1.319      | -0.076   |
| 100        | 1.400       | 1.393      | -0.503   |